

(19) World Intellectual Property
Organization
International Bureau



(43) International Publication Date
6 May 2005 (06.05.2005)

PCT

(10) International Publication Number
WO 2005/041470 A1

(51) International Patent Classification⁷: **H04L 1/20, 1/24**

(21) International Application Number:
PCT/EP2004/005727

(22) International Filing Date: 27 May 2004 (27.05.2004)

(25) Filing Language: English

(26) Publication Language: English

(30) Priority Data:
03 022 922.3 9 October 2003 (09.10.2003) EP

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(81) Designated States (unless otherwise indicated, for every
kind of national protection available): AE, AG, AL, AM,
AT, AU, AZ, BA, BB, BG, BR, BW, BY, BZ, CA, CH, CN,
CO, CR, CU, CZ, DK, DM, DZ, EC, EE, EG, ES, FI, GB,
GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG,
KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD, MG,
MK, MN, MW, MX, MZ, NA, NI, NO, NZ, OM, PG, PH,
PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, SY, TJ, TM, TN,
TR, TT, TZ, UA, UG, US, UZ, VC, VN, YU, ZA, ZM, ZW.

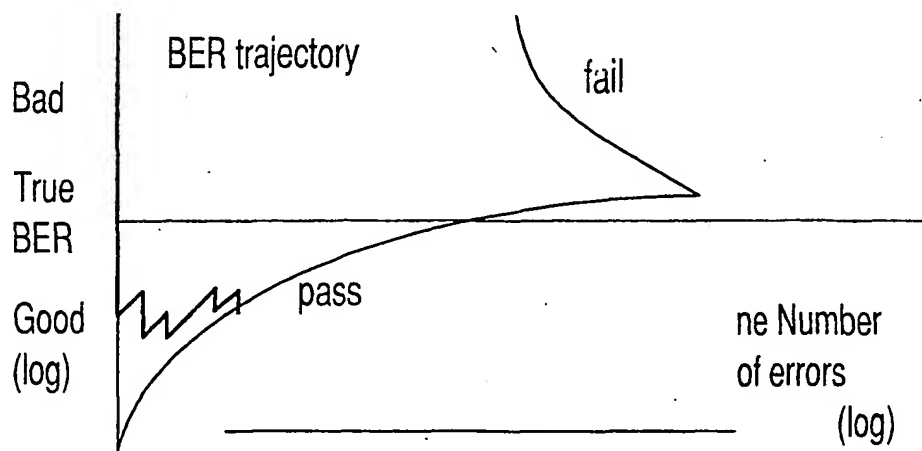
(84) Designated States (unless otherwise indicated, for every
kind of regional protection available): ARIPO (BW, GH,
GM, KE, LS, MW, MZ, NA, SD, SL, SZ, TZ, UG, ZM,
ZW), Eurasian (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM),
European (AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI,
FR, GB, GR, HU, IE, IT, LU, MC, NL, PL, PT, RO, SE, SI,
SK, TR), OAPI (BF, BJ, CF, CG, CI, CM, GA, GN, GQ,
GW, ML, MR, NE, SN, TD, TG).

Published:

— with international search report

For two-letter codes and other abbreviations, refer to the "Guid-
ance Notes on Codes and Abbreviations" appearing at the begin-
ning of each regular issue of the PCT Gazette.

(54) Title: METHOD FOR TESTING THE ERROR RATIO BER OF A DEVICE ACCORDING TO CONFIDENCE LEVEL,
TEST TIME AND SELECTIVITY



(57) Abstract: A method for testing the error ratio BER of a device under test against a specified allowable error ratio comprises the steps: measuring ns samples of the output of the device, thereby detecting ne erroneous samples of these ns samples, defining BER(ne)=ne/ns as the preliminary error ratio and deciding to pass the device, if the preliminary error ratio BER(ne) is smaller than an early pass limit EPL (ne). The early pass limit is constructed by using an empirically or analytically derived distribution for a specific number of devices each having the specified allowable error ratio by separating a specific portion DD of the best devices from the distribution for a specific number of erroneous samples ne and proceeding further with the remaining part of the distribution for an incremented number of erroneous samples.